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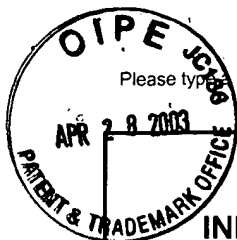
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)				Application Number	10/047,976
				Filing Date	1/13/02
				First Named Inventor	Steven Teig
				Group Art Unit	2825
				Examiner Name	
Sheet	1	of	1	Attorney Docket Number	SPLX.P0084

U.S. PATENT DOCUMENTS						
Examiner* Initials	Cite No. ¹	U.S. Patent Document Number Kind Code* (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
VS	1.	2001/ 0003843	A1	Scepanovic et al.	06-14-01	
	2.	4,615,011		Linsker	09-30-86	
	3.	4,673,966		Shimoyama	06-16-87	
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Substitute for form 1449A/PTO

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(use as many sheets as necessary)

Sheet	2	of	2	Application Number	10/047,976
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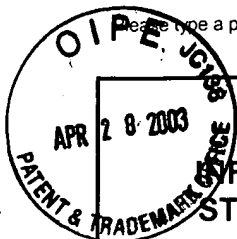
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VS	52.	6,516,455	B1	Teig et al.	02-04-03	

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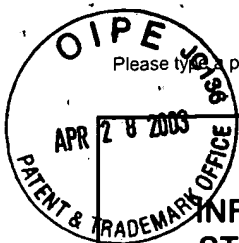
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VS	53.	6,516,455	B1	Teig et al.	02-04-03	
VS	54.	2003/0025 205	A1	Shively	02-06-03	

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Examiner* Initials	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Office ³	Number ⁴	Kind Code (if known) ⁵				
VS	55.	JP	64-15947		Ouchi	01-19-89		
VS	56.	JP	04000677		Fujiwara et al.	01-1992		

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				Group Art Unit	2835
				Examiner Name	
Sheet	4	of	4	Attorney Docket Number	SPLX.P0084

OTHER PRIOR ART – NON PATENT LITERATURE DOCUMENTS

Examiner* Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ⁶
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OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
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